NEWSdm

PLASMON ANALYSIS

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- Plasmon response with the current setup of the optical system
- Barycenter shift with Carbon Ion samples
- Study of brightness stability after the microscope optimization

NP40nm



Microscope optimization in terms of brightness response for each polarization angle (T. Asada, A. Alexandrov)



Number of clusters for each polarization angle (NP40nm)

The current setup on the other side shows now a very large anisotropy The source of this anisotropy has not been studied yet



Phi angle distribution – Expected isotropic (NP40nm)

Anisotropy affects mainly rotating grains, i.e. static grains without any preferred direction



 $\Delta \Phi$ is the maximum angular distance between two polarizations of the same collection



 $\Delta \Phi$ versus Φ

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Reduction of the anisotropy with $\Delta \Phi < 1$

 $\Delta \Phi$ is the maximum angular distance between two polarizations of the same collection



Only 5.7% of dataset survives

C 100 keV

Signal is mainly contained in the $0 < \Delta \Phi < 1$ region



Phi angle distribution

 $\Delta \Phi$ versus Φ

No cut on $\Delta \Phi$

No barshift cuts Barshift > 30nm Barshift < 30nm

Cut on $\Delta \Phi < 1$



Phi angle distribution

C 60 keV



Signal is mainly contained in the $0 < \Delta \Phi < 1$ region



 $\Delta \Phi$ versus Φ

Phi angle distribution

No cut on $\Delta \Phi$

No barshift cuts Barshift > 30nm Barshift < 30nm

Cut on $\Delta \Phi < 1$





Phi angle distribution



Phi angle distribution

C 30 keV Vertical



No signal expected in the $0 < \Delta \Phi < 1$ region

A clear instrumental peak is present around 0 rad



Phi angle distribution

 $\Delta \Phi$ versus Φ

No cut on $\Delta \Phi$

No barshift cuts Barshift > 30nm Barshift < 30nm

Cut on $\Delta \Phi < 1$



Phi angle distribution – Instrumental peak still present

C 30 keV Horizontal 90°



Signal expected in the $0 < \Delta \Phi < 1$ region

A clear instrumental peak is present around 0 rad



Phi angle distribution

 $\Delta \Phi$ versus Φ

No cut on $\Delta \Phi$

No barshift cuts Barshift > 30nm Barshift < 30nm

Cut on $\Delta \Phi < 1$



Phi angle distribution – Instrumental peak still present

Signal peak evident after cut

C 30 keV Horizontal 135°



Signal expected in the $0 < \Delta \Phi < 1$ region

A clear instrumental peak is present around 0 rad



Phi angle distribution

 $\Delta \Phi$ versus Φ

No cut on $\Delta \Phi$

No barshift cuts Barshift > 30nm Barshift < 30nm

Cut on $\Delta \Phi < 1$



Phi angle distribution - Instrumental peak still present

Signal excess visible after cut

PDF Ratio between C 30 keV ion horizontal samples and vertical sample

Expected: 90° - Measured: 90°

Expected: 135° - Measured: 136°



Preliminary study on brightness



NP 40 nm



Brightness of the clusters over the mean background Maximum variation of the background for each collection

10g Test sample



Brightness of the clusters over the mean background Maximum variation of the background for each collection

C 60 keV



Brightness of the clusters over the mean background Maximum variation of the background for each collection

Preliminary investigation of new variables to exploit the brightness information





Distribution of maximum of the brightness over the mean background

Conclusions

- The optimization of microscope in terms of brightness stability makes it possible to include the brightness in the plasmon analysis
- On the other side, the new setup produces a new source of anisotropy that needs to be reduced since it affects the efficiency of the signal observation
- The amplitude of phi angle of the collection was used to reduce the anisotropy
- A signal observation for C30keV has been achieved

PERSPECTIVES

- Study of the brightness information (any ideas?)
- Comparison of brightness for candidates after ellipticity cut (TestSample) with Carbon ion sample
- Estimation of plasmon analysis power discrimination

BACKUP



PLASMON ANALYSIS OVERVIEW

NEWSdm analysis strategy consists of a two-step approach:

- 1. Elliptical shape analysis for candidate selections (currently done in Nagoya)
- 2. Plasmon analysis for validation of candidates (currently done in Napoli)

Grains with track length about the optical resolution limit (~200 nm) appear like a single cluster.

A single cluster therefore may consist of:

- one grain and would appear like spherical (fog-like)
- two grains inside and would have an elliptical shape (signal-like)

Elliptical shape analysis makes a selection exploiting the ellipticity of the clusters

Plasmon analysis validates the candidates looking at the cluster properties when observed with different polarization of incident light

View dimension: 61 x 48 um² Pixel size: ~ 27.6 nm

Cluster (2D)

Grain (3D)

Bfcl (2D)



The best focus cluster frame (bfc-fr) is the frame containing the brightest cluster. It is calculated for each polarization angle

Graining process

Max dist between

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For each candidate 8 measurement with different polarization angle

(0°, 22.5°, 45°, 67.5°, 90°, 112.5°, 135°, 157.5°) clusters (XY) ~ 300nm

View

PLASMON VARIABLES

• Clusters (2D objects within the frame) \rightarrow different polarization angles

Grains (3D objects) \rightarrow (obtained from linked clusters) :

x 8 • Clusters ---- • Best focus clusters ---- Best focus cluster frames

List of variables:

- Npol \rightarrow Number of polarizations linked to the grain
- 1peak \rightarrow Grains with one brightness peak in the bfc-fr
- Npeaks \rightarrow Grains with two or more brightness peaks in the bfc-fr
- Barshift \rightarrow Max displacement of the barycenter over all the best focus clusters

Npol = 8 (total number of polarization angles) is needed for a full and reliable analysis



PLASMON VARIABLES



Exploiting the resonance effect of polarized light:

• brightness variation;

Useful to find clusters with two (or more) brightness peak

• displacement of the barycenter of the cluster; A large displacement means the presence of two or more grains within the cluster

TOPOLOGICAL **V**ARIABLES

List of variables:

- Npol \rightarrow Number of polarizations linked to the grain
- **1peak** \rightarrow Grains with one brightness peak in the bfc-fr
- Npeaks \rightarrow Grains with two or more brightness peaks in the bfc-fr
- Barshift \rightarrow Displacement of the barycenter over all the best focus clusters

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New topological variables:

• PathLen \rightarrow Path length of the barycenter from polarization 0°



• MaxAmp \rightarrow Max distance from the Barshift line





Barshift threshold is not enough to distinguish signal-like from fog-like events

These new variables could improve the characterization of 1peak clusters

- BarShift \rightarrow Displacement of the barycenter over all the best focus clusters
- PathLen \rightarrow Path length of the barycenter from polarization 0°
- MaxAmp \rightarrow Max distance from the Barshift line



- BarShift \rightarrow Displacement of the barycenter over all the best focus clusters
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Signal-like events have a Regularity Index peaked at 2 \rightarrow Very regular path Signal-like events have a Spread peaked around 0.1 \rightarrow Deviations from BarShift direction are small

LIST OF SAMPLES

- NP 40nm \rightarrow Nanoparticles
- C10 keV \rightarrow Carbon vertical ions

• C30 keV

C60 keVC100 keV

Carbon horizontal ions

C150keV \rightarrow Carbon vertical ions

10gTS \rightarrow 10g test sample

Background studies

Signal-like events

Gelatine layer on top surface

Rejection power of plasmon analysis on candidates

NP 40_{NM}

1Peak clusters BarShift > 30nm : 11.72 %

Displacement of the barycenter



Mean BarShift ~ 20nm





Not-physical anisotropy

C10keV

1Peak clusters BarShift > 30nm : 21.14 %



POSITION ACCURACY

NP40nm Entries Mean 2124 -1.908 RMS 7.29 69.63 / 18 χ^2 / ndf 500 458.8 ± 14.1 -1.837 ± 0.142 Constant Mean 6.431 ± 0.138 Sigma 400 300 200 100 -50 -40 -30 -20 -10 0 10 20 30 40 x displacement [nm] Entries 2121 700 Mean -2.035 RMS 6.316 50.33 / 14 χ^2 / ndf 618.9 ± 18.4 Constant 600 -2.017 ± 0.123 Mean Siam 5.606 ± 0.113 500 400 300 200 100 0 -40 -20 20 40 0 y displacement [nm]



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Improvements in the position accuracy

The accuracy achieved in the position of the grains is ~ 5nm C100keV

1Peak clusters BarShift > 30nm : 55.24 %



Phi angle distribution

Peak at 0° degrees

C60keV

1Peak clusters BarShift > 30nm : 46.67 %



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C30keV

1Peak clusters BarShift > 30nm : 39.90 %

FROM SRIM

Mean track length ~ 86nm

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Mean BarShift ~ 31nm





Small peak around 0° degrees

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Nanotracks vs Microtracks



A larger fraction of microtracks is found for C100keV sample while the contribution of microtracks is not visible for C30keV sample, where the tracks are expected to be made of one grain only

TEST SAMPLE 10g

1Peak clusters BarShift > 30nm : 16.66 %

Displacement of the barycenter



Mean BarShift ~ 22nm

Phi angle distribution



Not-physical anisotropy

SIGNAL SELECTION (C30keV)

Regularity index and Spread cuts have been used to reduce the anisotropy

Regularity Index < 2.3 Spread < 0.18



A signal can be observed in the 0° orientation and barely in the 45° orientation At 90° the signal disappear \rightarrow Anisotropy effect? , Low contrast?

SIGNAL SELECTION

Regularity Index < 2.3 Spread < 0.18





Anisotropy seems to be reduced after cuts on the topological variables

0

0.5

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REGULARITY VS **B**ARSHIFT



In order to reduce the background contamination several cuts should be applied For example, in addition to BarShift > 30nm an upper cut at 2.5 on Regularity Index improve the background rejection

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Spred vs Phi Angle



Samples with grains with preferred direction have a smaller Spread (~0.2)



C150keV

- Gelatine layer on top surface
- Vertical ions exposure

1Peak clusters BarShift > 30nm : 58.71 %

Displacement of the barycenter







Mean BarShift ~ 37nm

C150keV Matching



Japanese predictions allow to find the candidates from elliptical shape selection in Napoli scanning data with an accuracy less than 200 nm

Conclusions

- Position accuracy of 5 nm achieved with plasmon analysis
- Signal directional peak detected for C60keV
- Small directional peak observed also in C30keV

PERSPECTIVES

- Analysis of C40keV and C50keV useful to evaluate the detection track length threshold
- Study of topological variables for signal / background discrimination
- Identification of new topological variables
- Larger sample of candidates needed to test the different selection cuts
- Use of **electronic microscope** needed to find the correlation between the shift of the barycenter and the real track length

THANK YOU

